

Update on CLICpix planar-sensor assembly simulations

- Simulation of the readout -

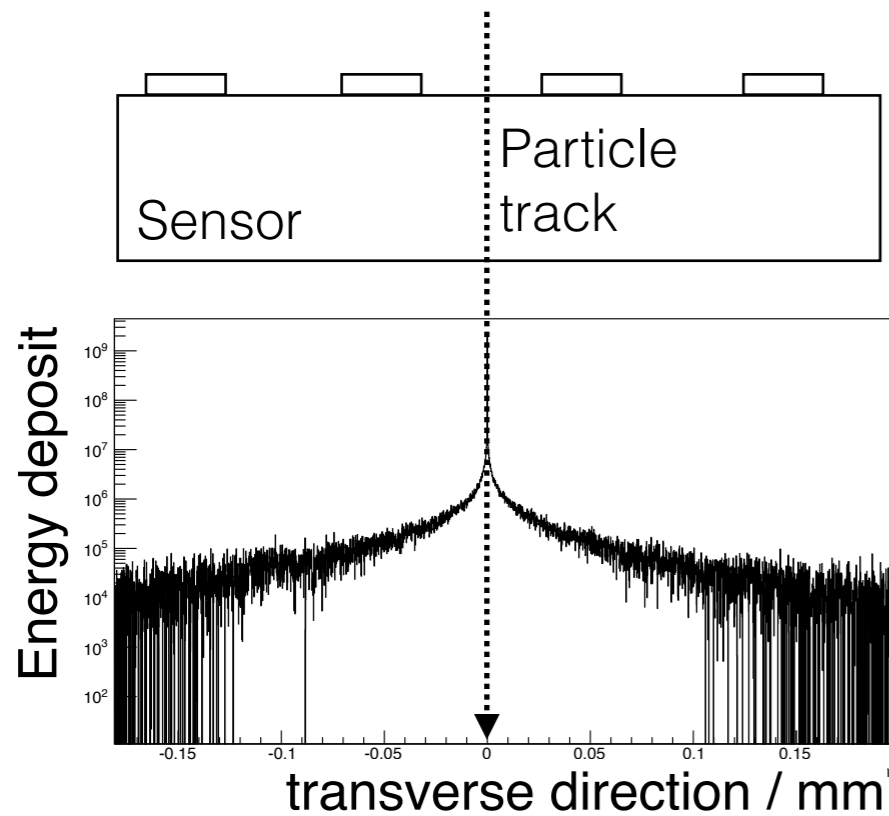
Magdalena Munker, Andreas Nürnberg

CLICdp Vertex-Meeting, 10.03.2016

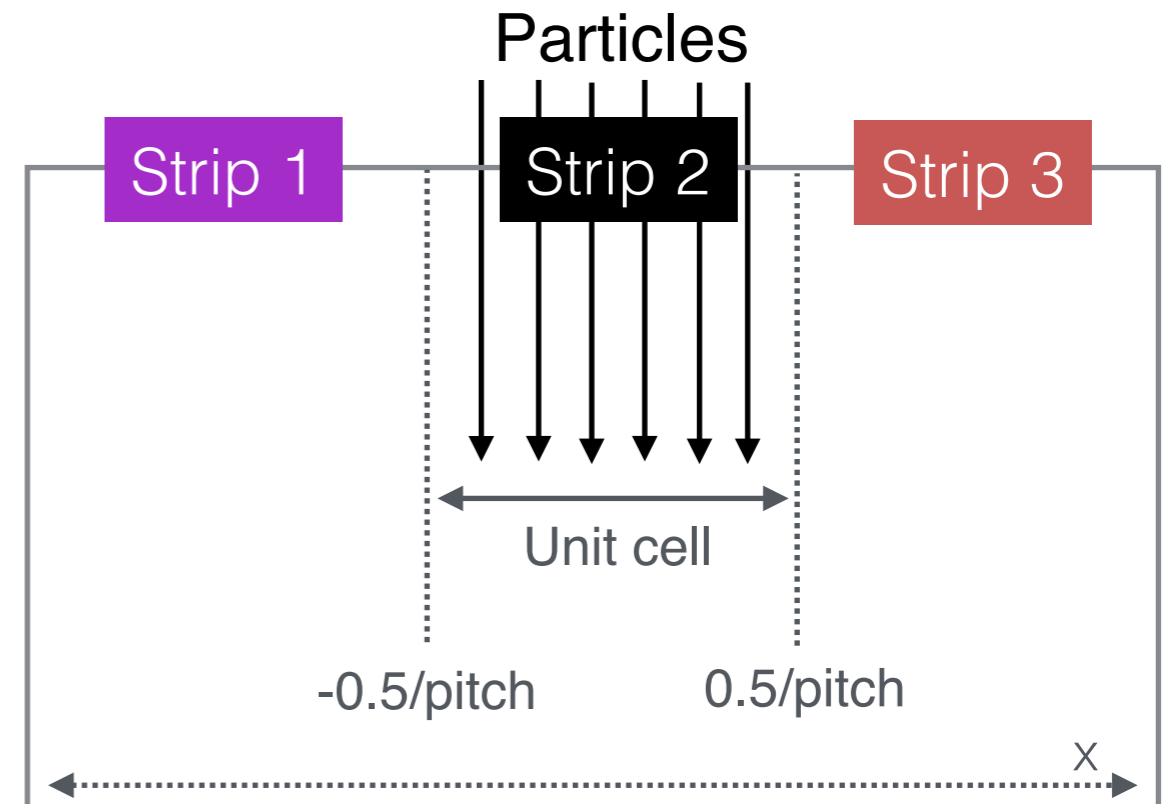


The simulation in a nutshell

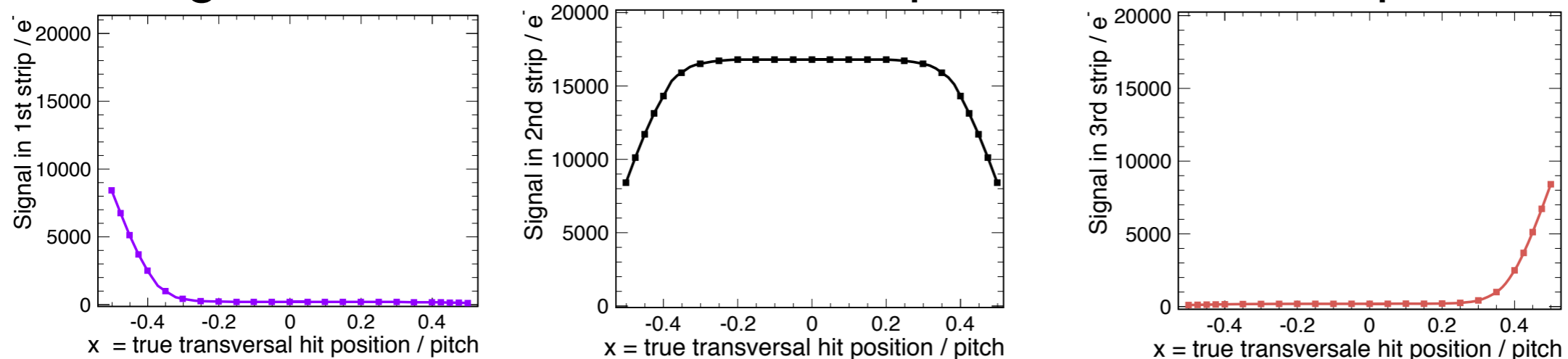
GEANT4 simulation of energy deposit in silicon sensor:



Finite element simulation of sensor with T-CAD:

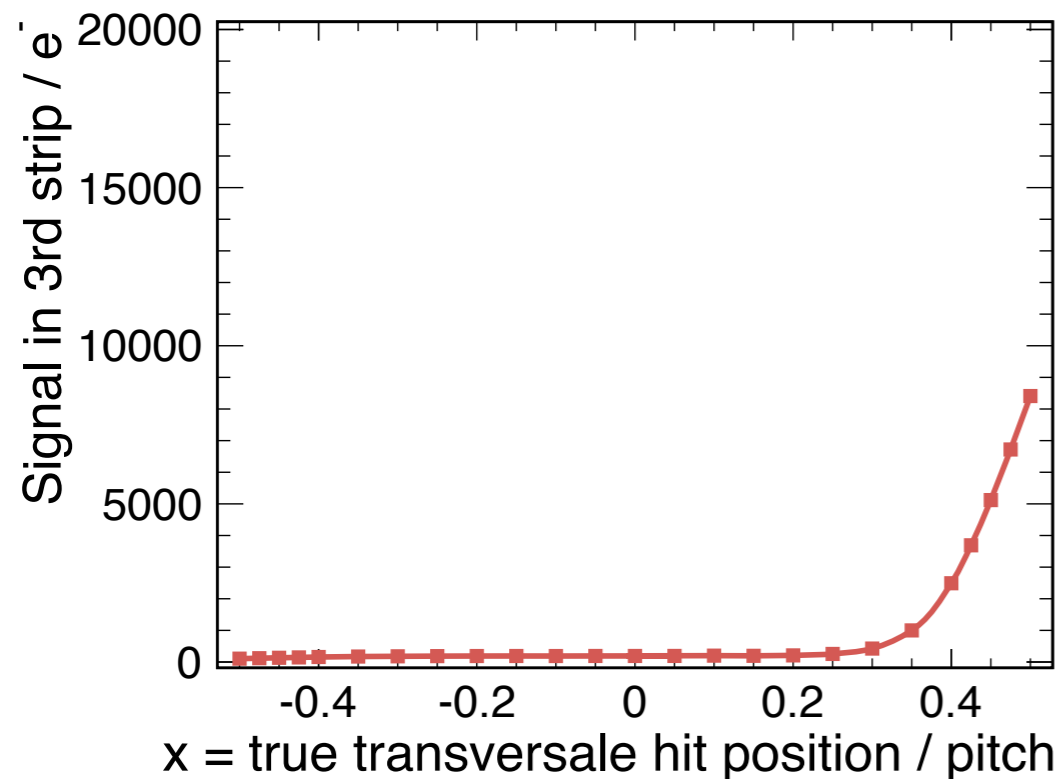


Fit to signal on different readout strips vs. transversal position x:



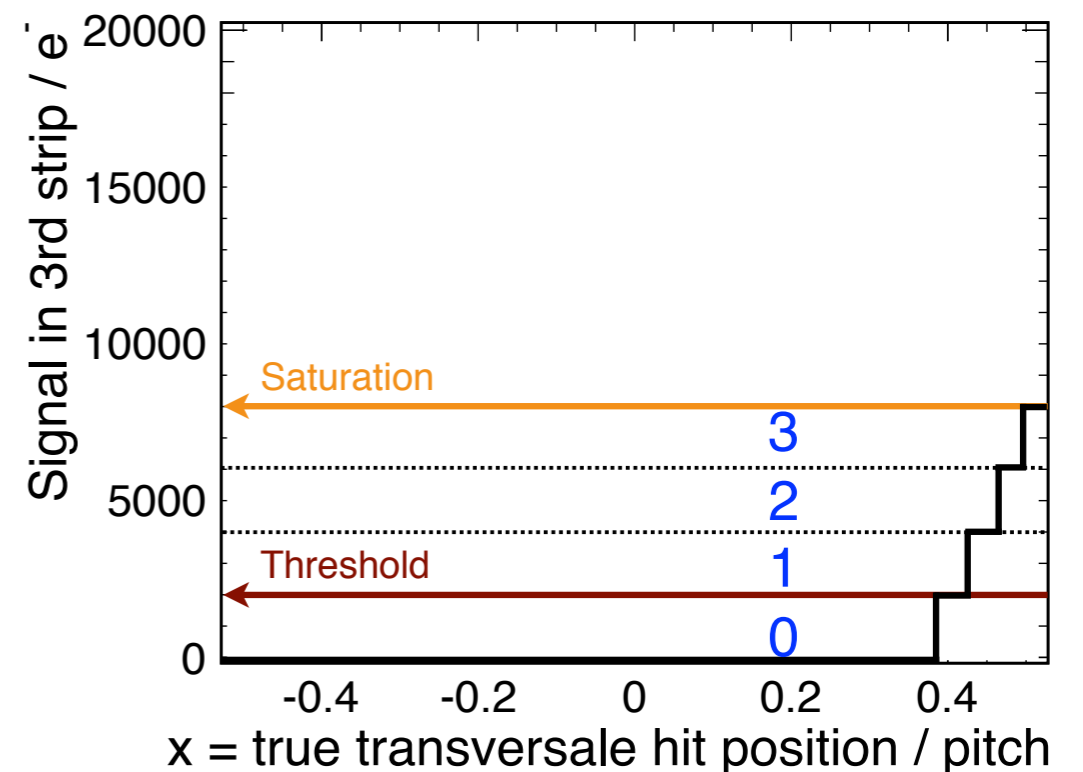
Digitalisation / implementation in the simulation

Analog information, interpolation of signal:



Digitalisation

Example of digitalisation with 2 bits (4 bit states):



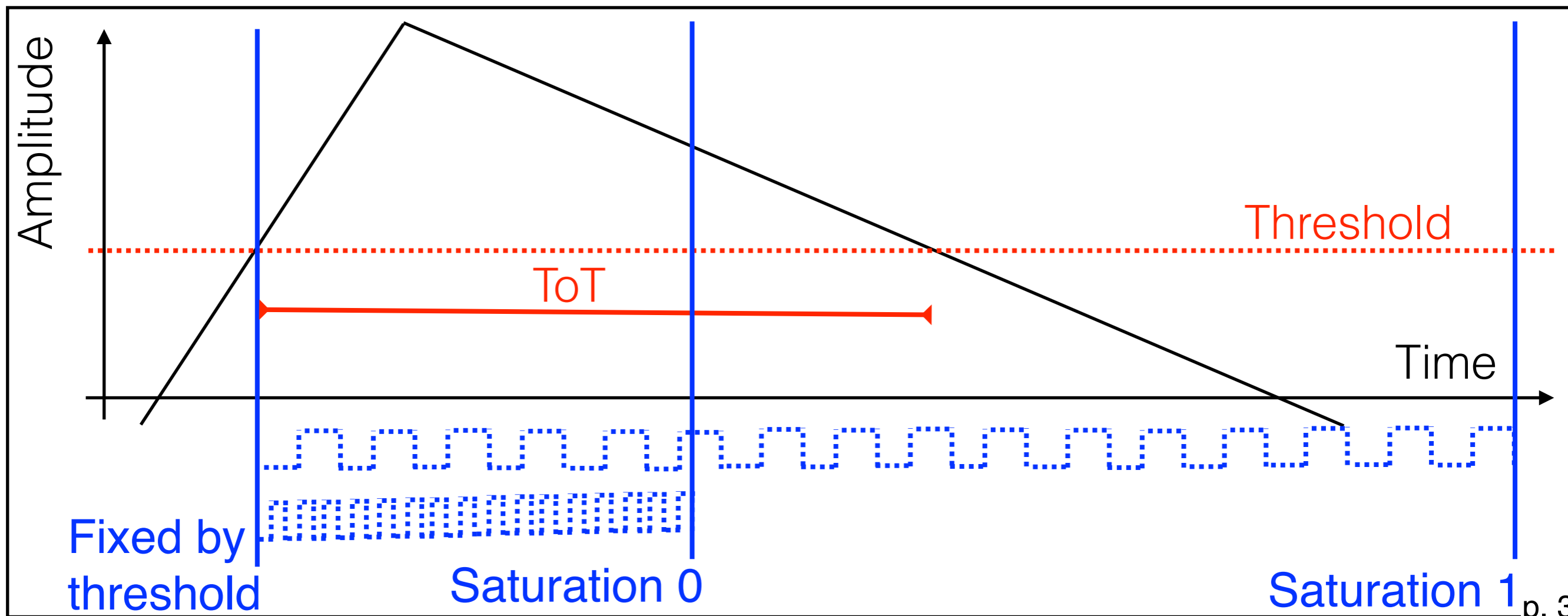
- Apply threshold
- Define saturation
- Define number of bits
- Equally spacing of bit states between threshold and saturation

3 parameters:

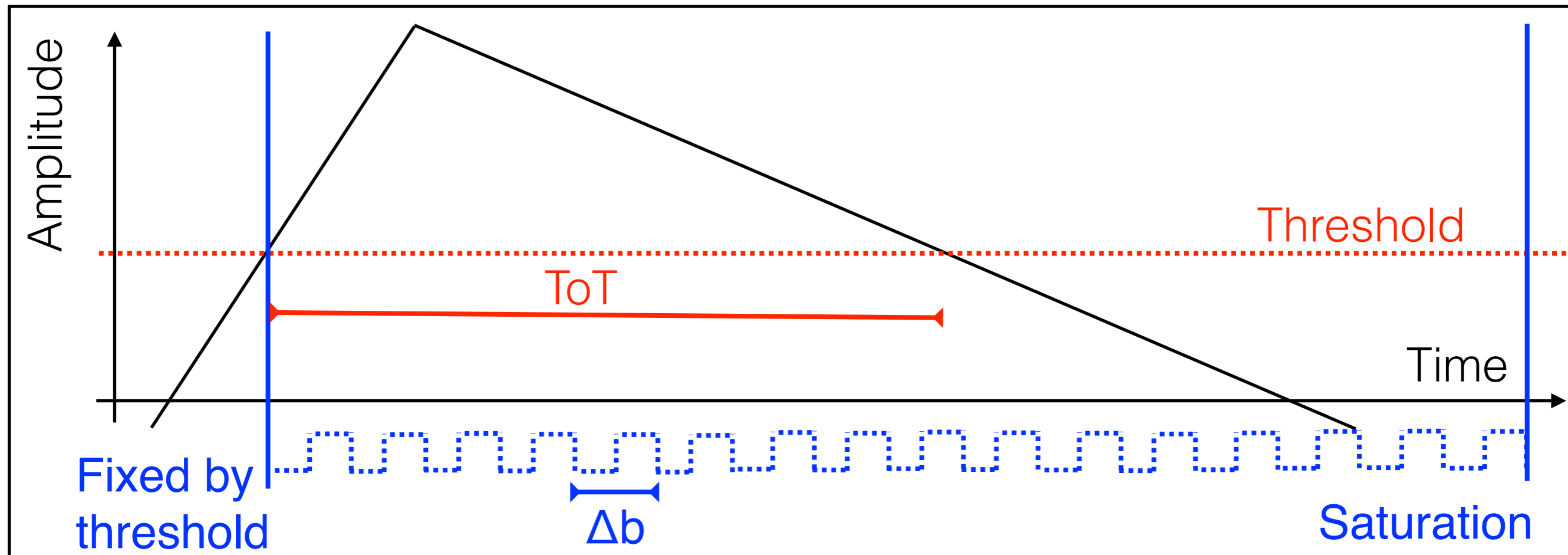
- Threshold
- Saturation
- Number of bits

Digitalisation / CLICpix test-beam data

- Data recorded during test-beam period in August 2015 at SPS with CLICpix planar-sensors of 200 μm thickness
- 200 MHz clock, ToT-readout
- Frequency = $200 \text{ MHz} / (\text{clock-division} + 1)$
- Scan of clock-division during data taking corresponds to **shift of saturation and precision** due to fixed number of 4 bits:



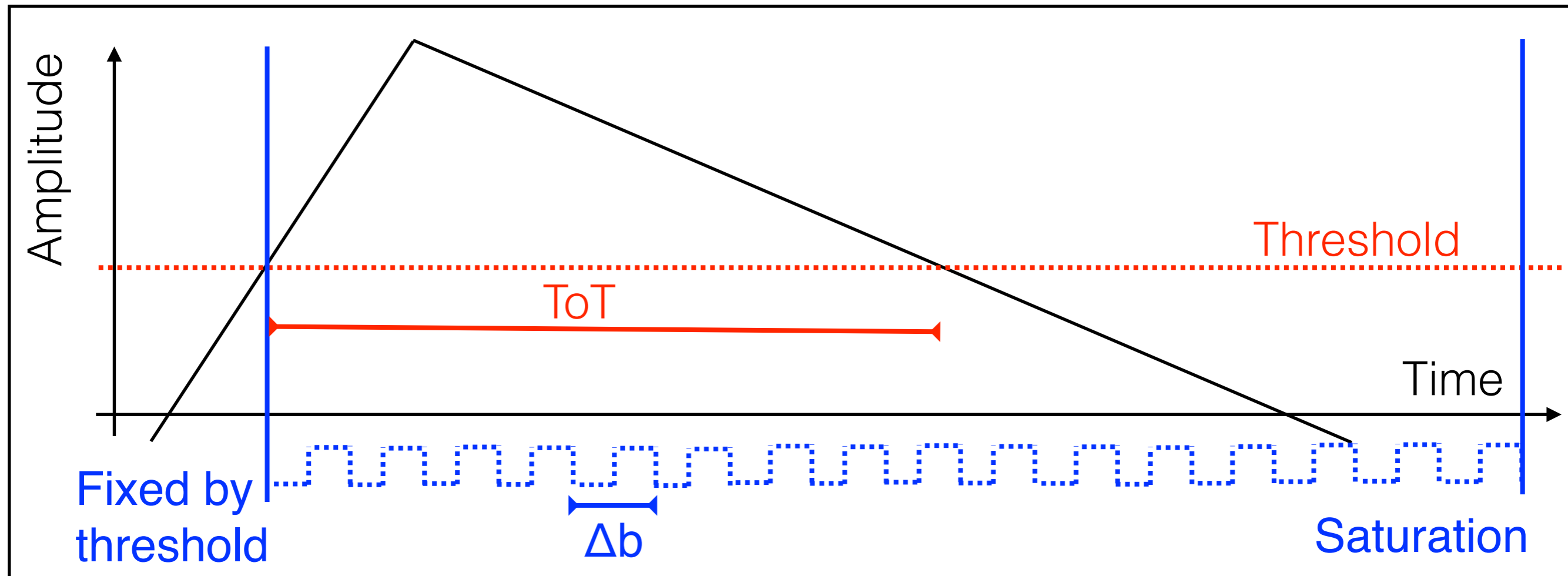
Digitalisation / comparison of CLICpix data to simulation



Need to convert the clock-division factor to an electron scale to compare clock-scan to simulation:

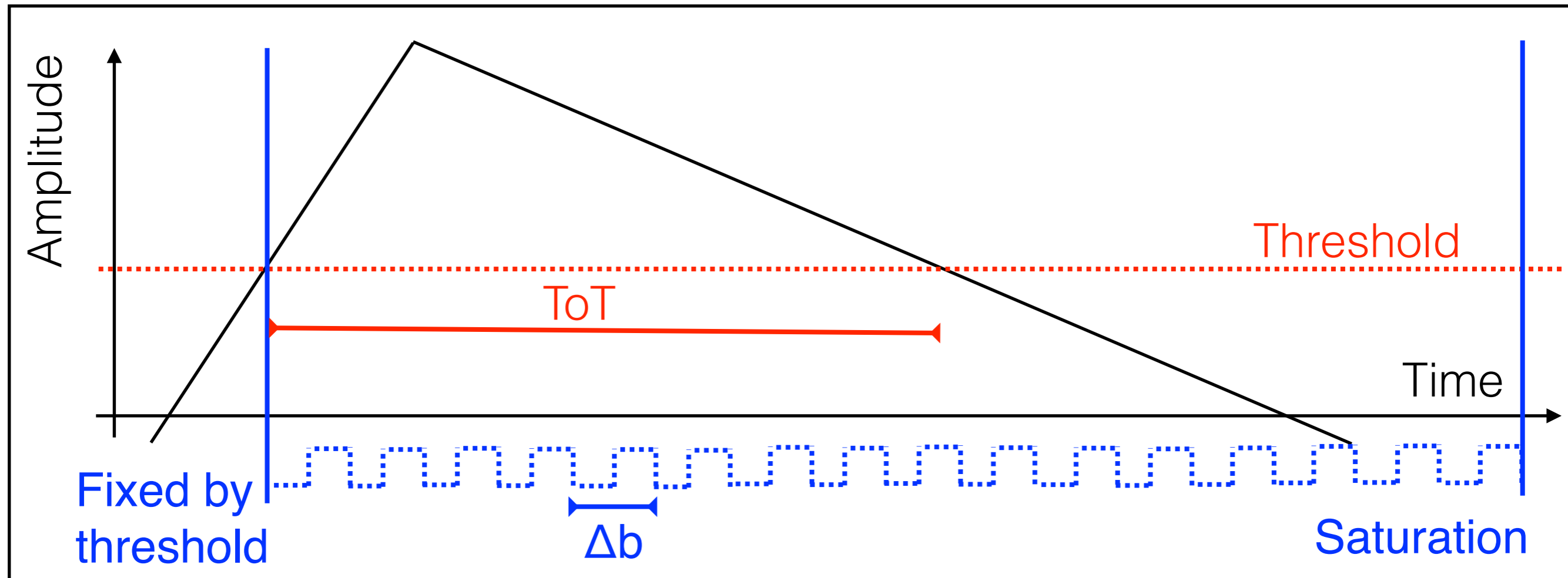
- Landau of cluster signal in units of Δb
- Select clock-division of 20 which does not saturate the signal
- Fit Landau \otimes Gauss \rightarrow MPV [$\Delta b(\text{clock-division}=20)$]

Digitalisation / comparison of CLICpix data to simulation



- Fit Landau \otimes Gauss \rightarrow MPV [$\Delta b(\text{clock-division} = 20)$]
- Sensor thickness of 200 μm \rightarrow MPV [$\Delta b(\text{clock-division} = 20)$] = 16000 e^-
- \rightarrow $\Delta b(\text{clock-division} = 20)$ [e^-] = 16000 e^- / MPV
- \rightarrow Fixed number of 4 bits:
 Saturation(clock-division = 20) [e^-] = $2^4 \times \Delta b(\text{clock-division} = 20)$ [e^-]

Digitalisation / comparison of CLICpix data to simulation



For arbitrary clock-division:

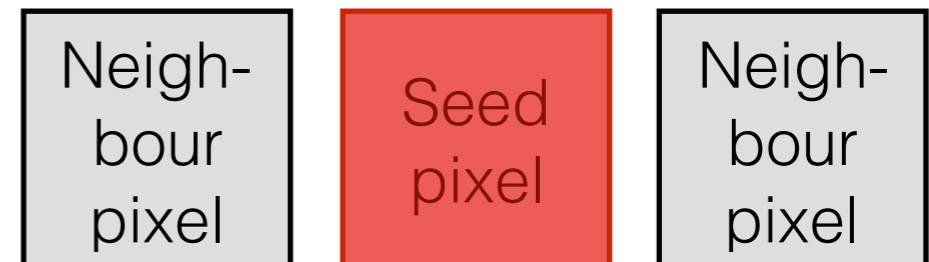
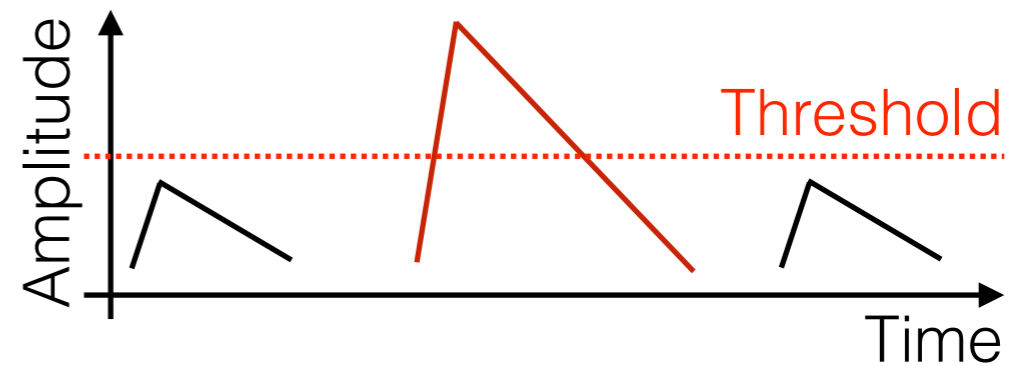
$$\Delta b(\text{clock-division}) [e^-] = (16000 / \text{MPV}) \times (\text{clock-division} + 1) / (20 + 1)$$

$$\text{Saturation}(\text{cd}) [e^-] = 2^4 \times \Delta b(\text{clock-division}) [e^-]$$

This can be used now to convert any clock-division in saturation $[e^-]$ for the simulation

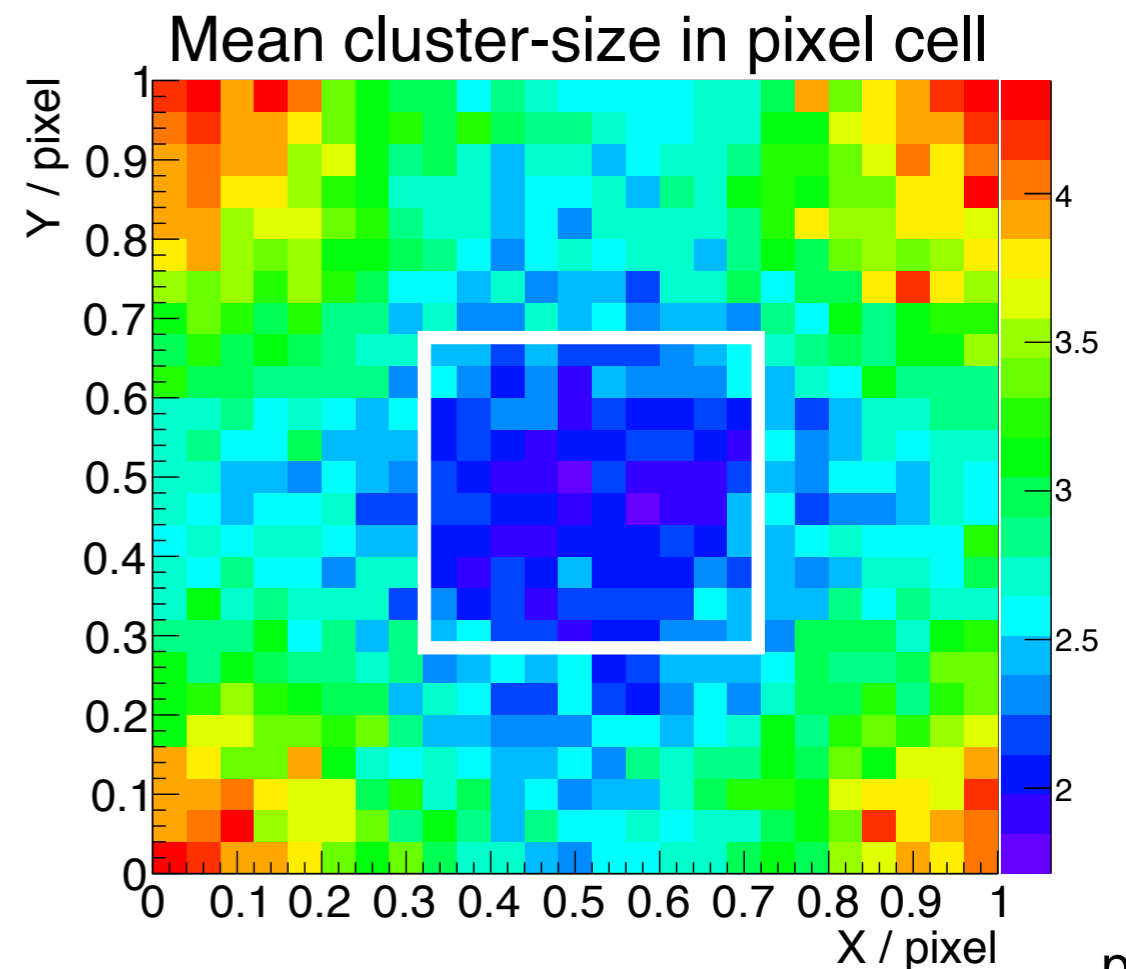
Landau \otimes Gauss fit / cut on sensor center

- Charge sharing
- Neighbour pixels might be below threshold
- Distortion of cluster-signal
- Need to avoid charge sharing

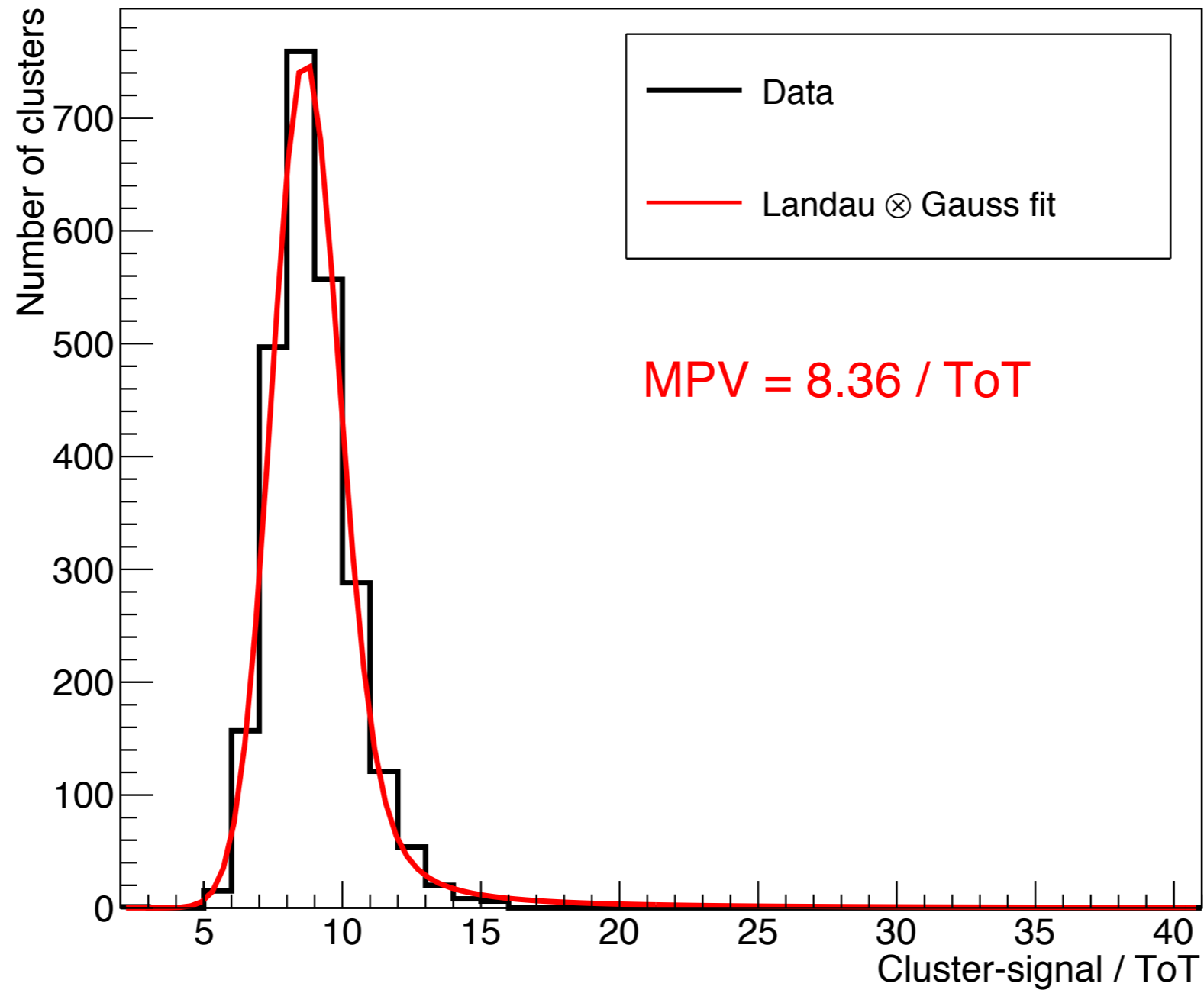


Avoid charge sharing by requiring cluster-size of 1 and cutting on sensor center

Select only hits in white box which have a cluster-size of 1



Landau \otimes Gauss fit / results for even columns



$$\Delta b(\text{clock-division}) [e^-] = (16000 / \text{MPV}) \times (\text{clock-division} + 1) / (20 + 1)$$

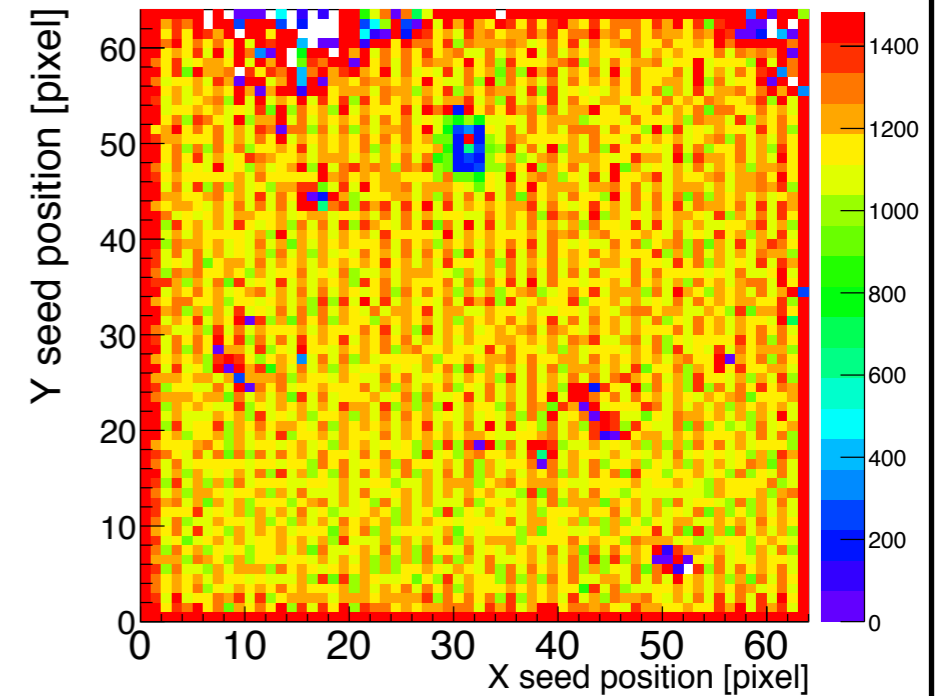
$$\text{Saturation(cd)} [e^-] = 2^4 \times \Delta b(\text{clock-division}) [e^-]$$

Cuts in the test-beam analysis

Why?:

Different response of odd and even columns in x-dimension because of known CLICpix issue:

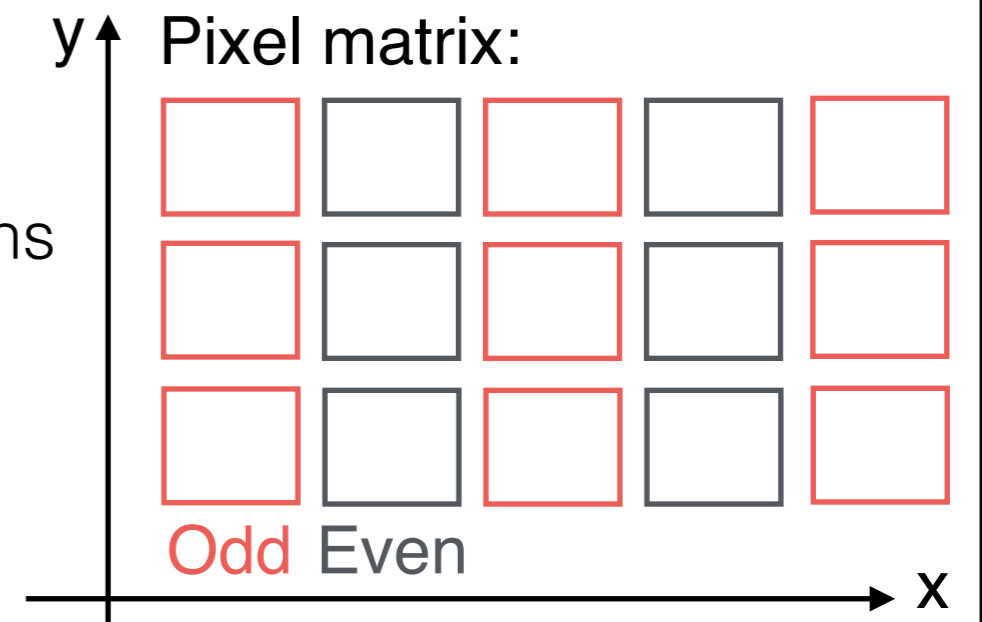
- Crosstalk from discriminator output to preamplifier
- Different for even and odd columns because of pixel layout



How?:

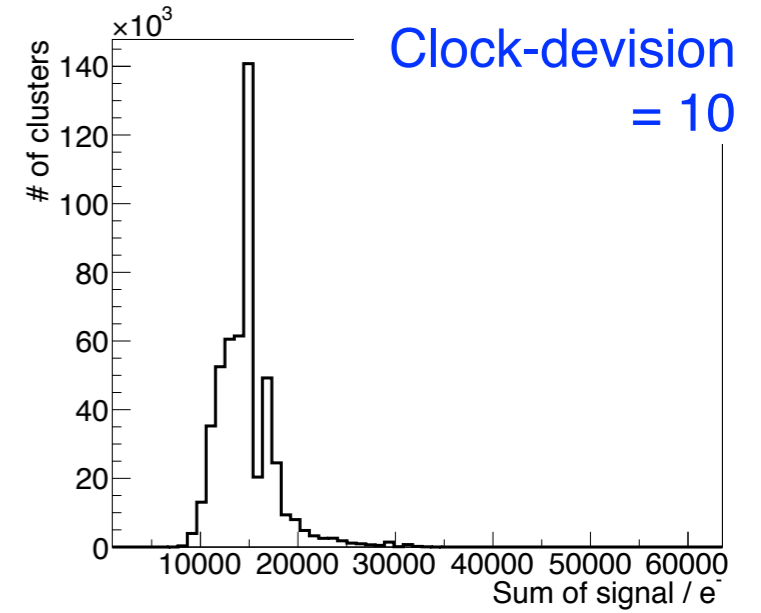
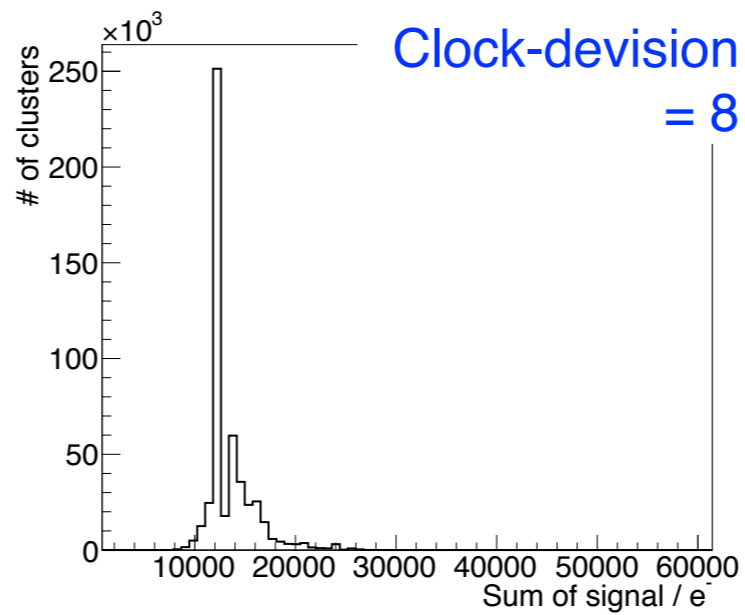
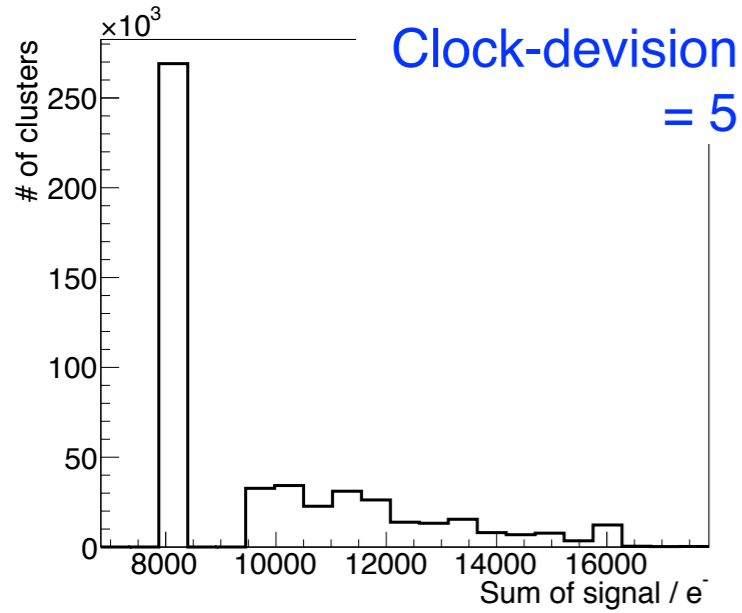
Force **cluster size in x-dimension to 1 & cut on sensor center:**

- Reduce charge sharing between odd & even columns
- **Study odd & even columns separately**
- Study **observables in y-dimension**
- **Show only results for even columns**

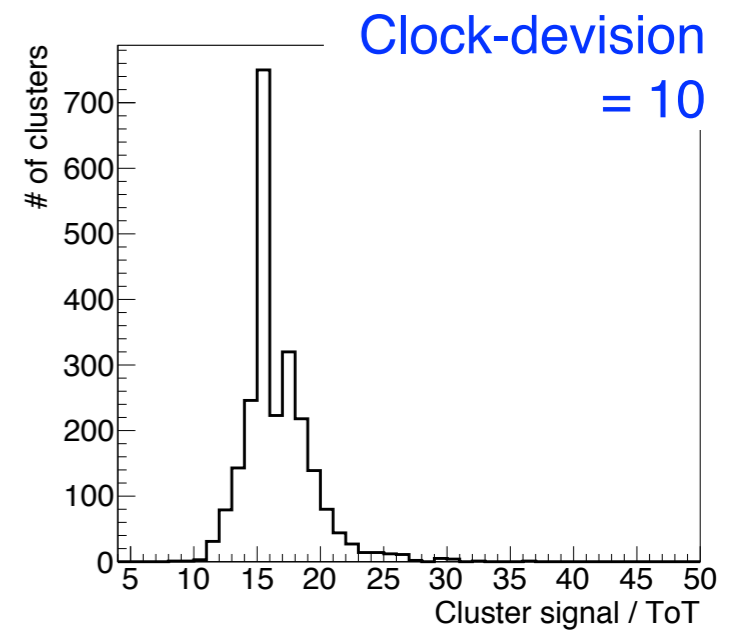
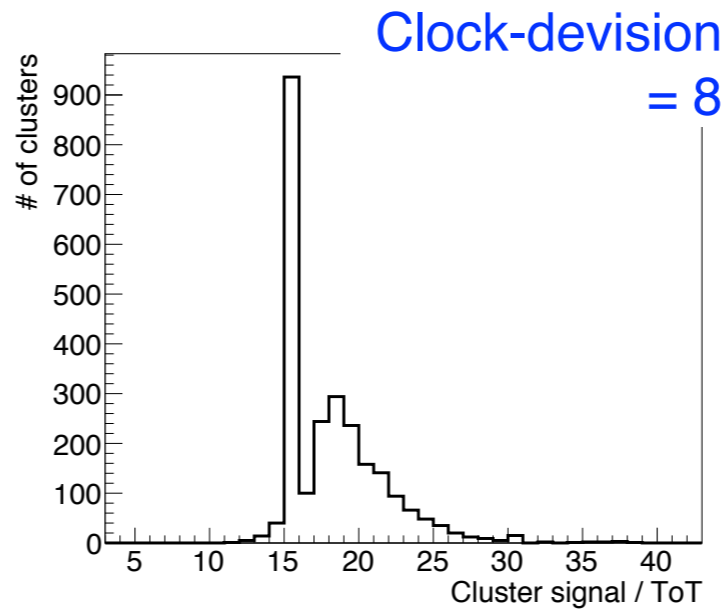
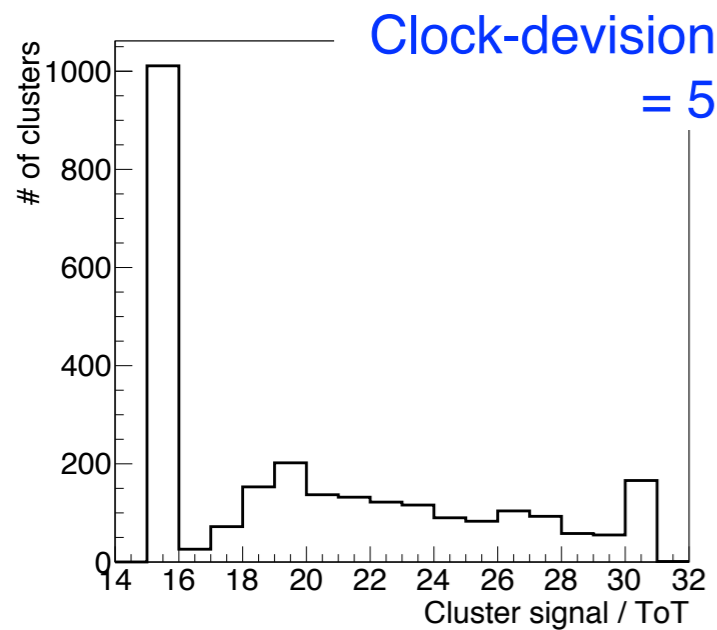


Landau for different clock deviations

Simulation:



Data:

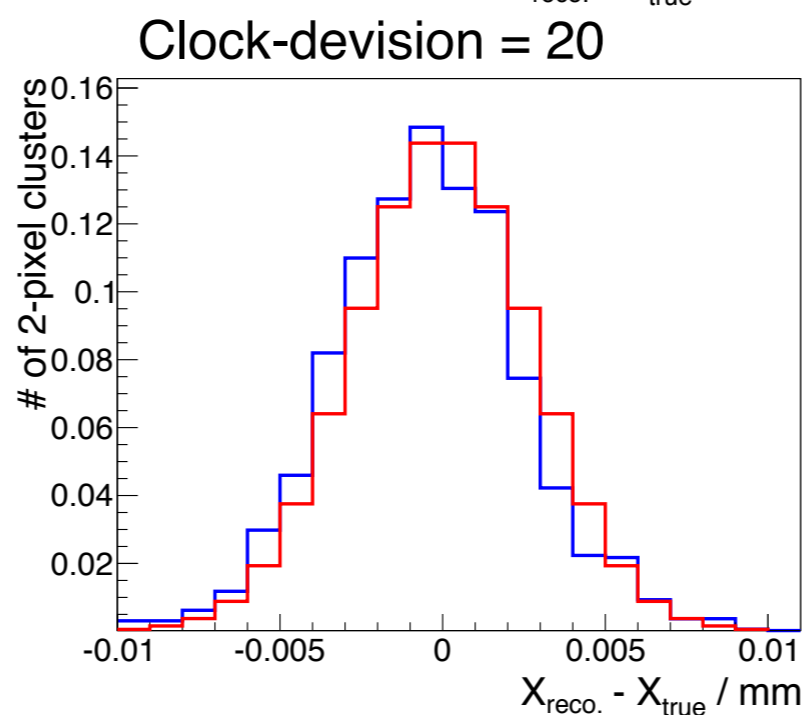
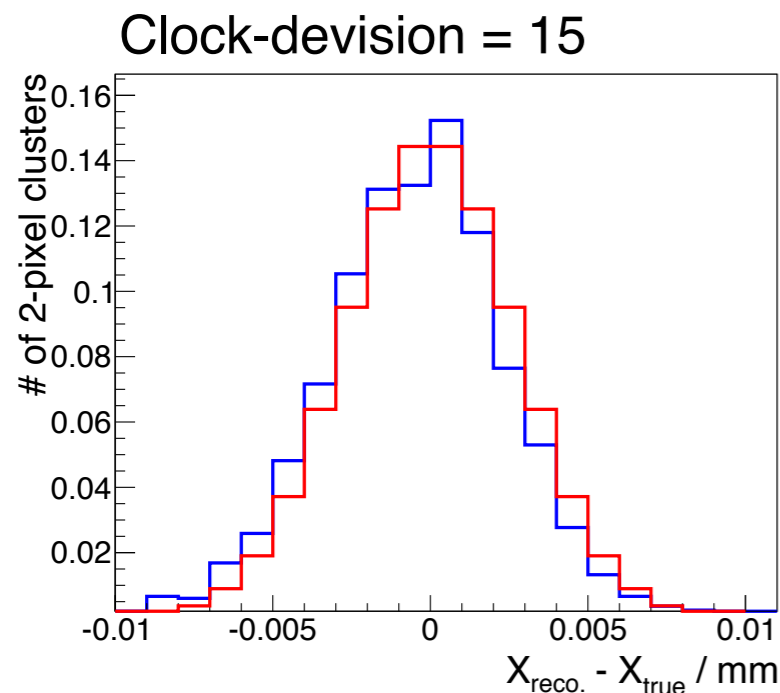
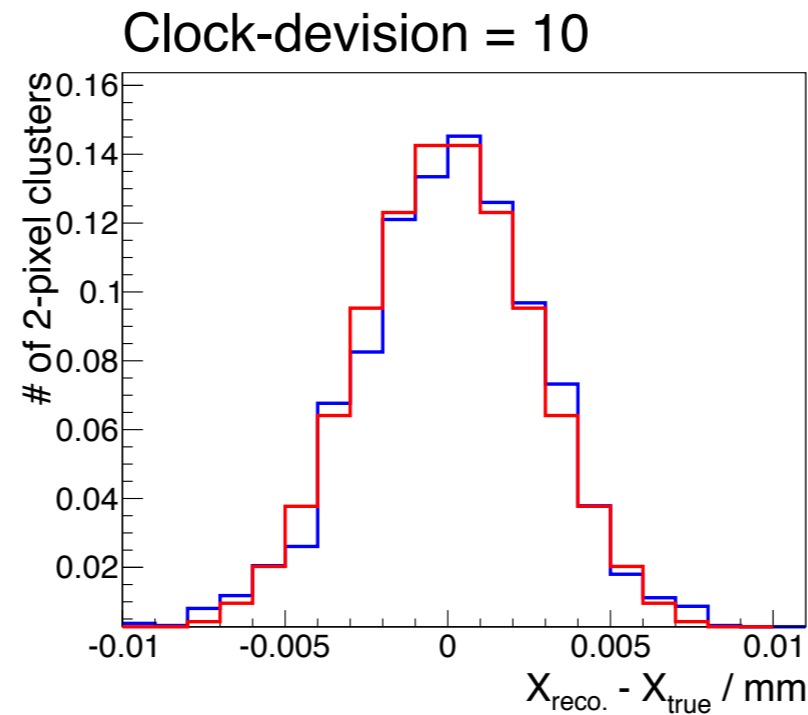
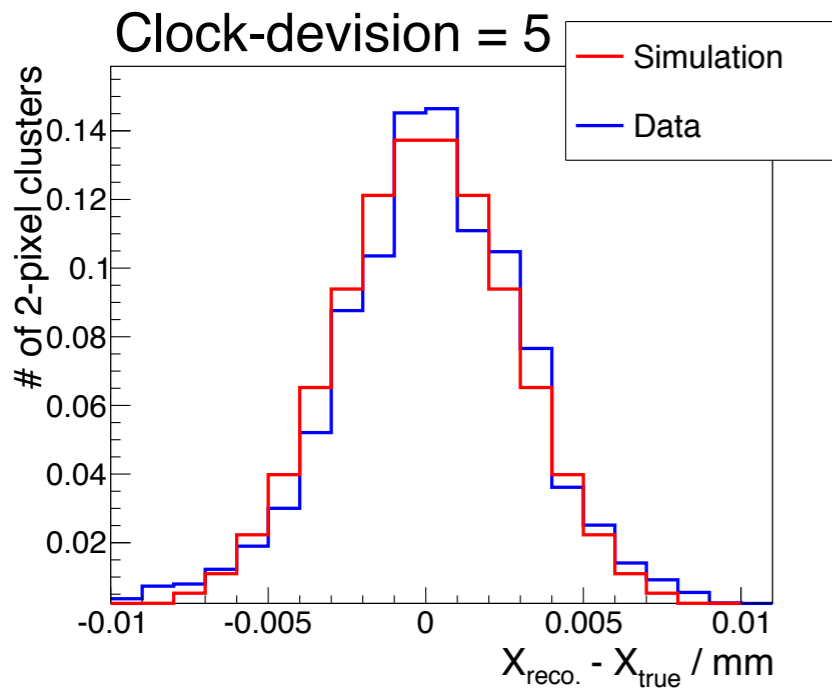


Good agreement!

Resolution versus clock division

- Single pixel cluster resolution always binary, independent from digitalisation

↳ Study 2-pixel cluster resolution for different clock divisions:



Simulation:

- $\sigma_{\text{Telescope}} = 2.5 \mu\text{m}$
- $\sigma_{\text{Noise}} = 150 e^-$
- $\sigma_{\text{Threshold}} = 22 e^-$

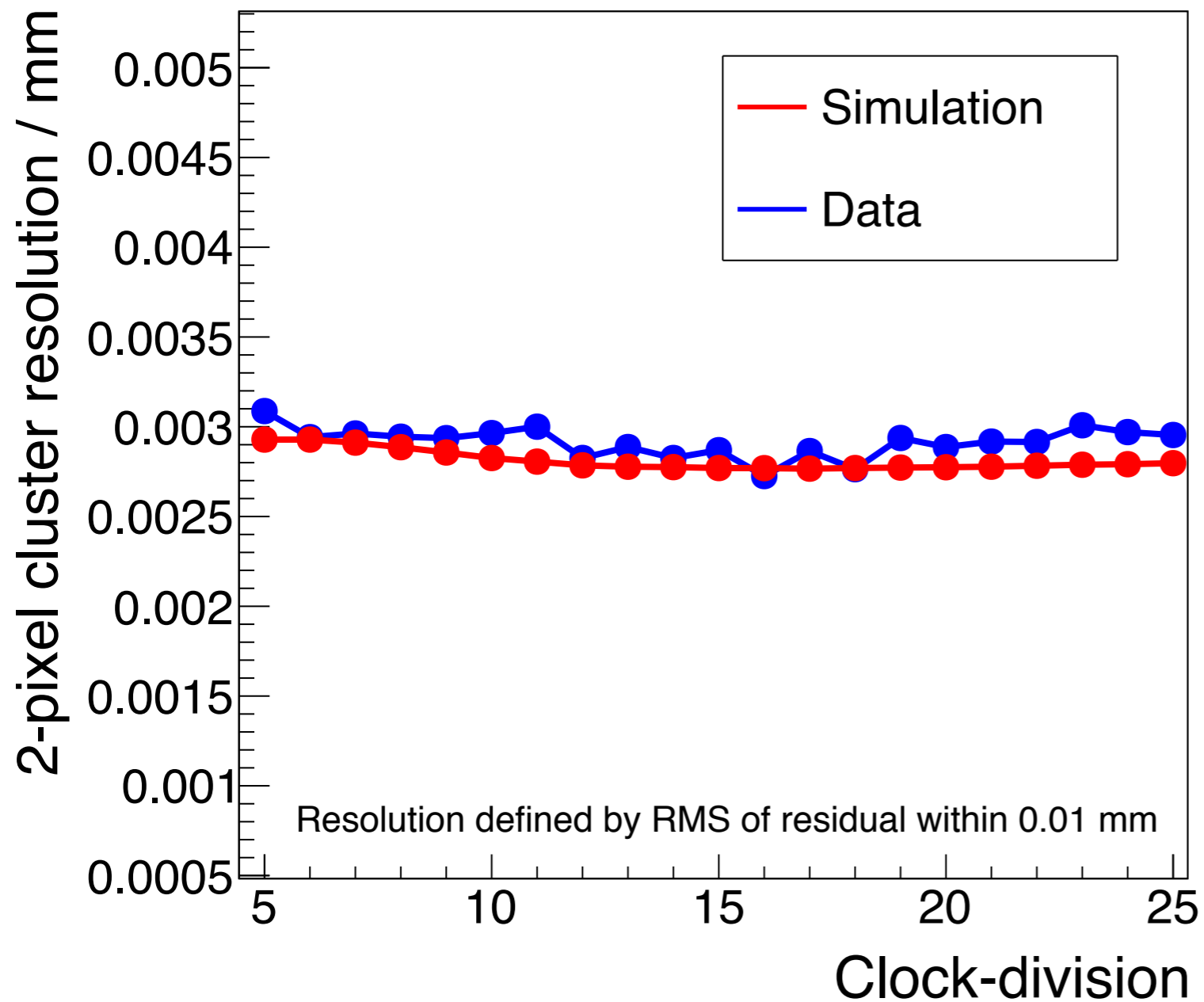
Excellent agreement.

Resolution versus clock division

Expectation:

- Very small clock division \rightarrow saturation of signal \rightarrow resolution gets worse
- Very large clock division \rightarrow loss of precision \rightarrow resolution gets worse

Observation:



No agreement between expectation & observation

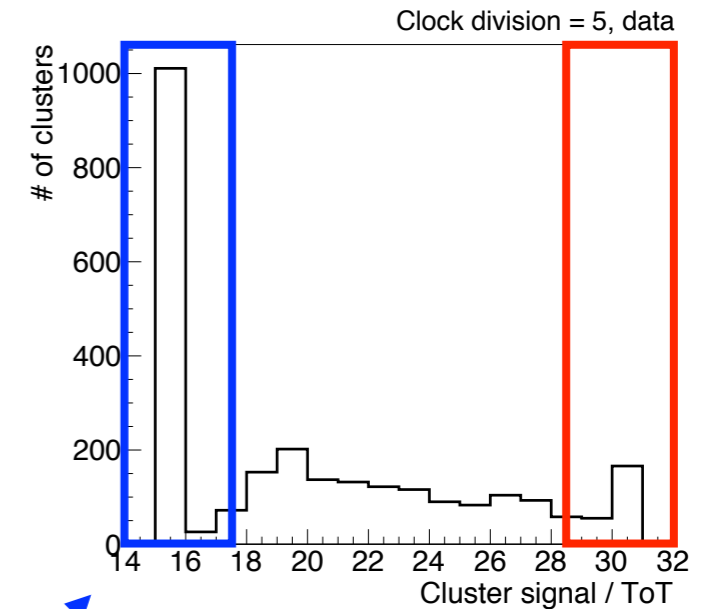
But agreement between data & simulation in Landau distributions & 2-pixel cluster resolution

Use the simulation to understand discrepancy between expectation & observation

Resolution versus clock division / even

Why does the resolution not gets worse for small clock-divisions?:

- For a clock division of 5 one still gets multi-pixel cluster Landau distribution

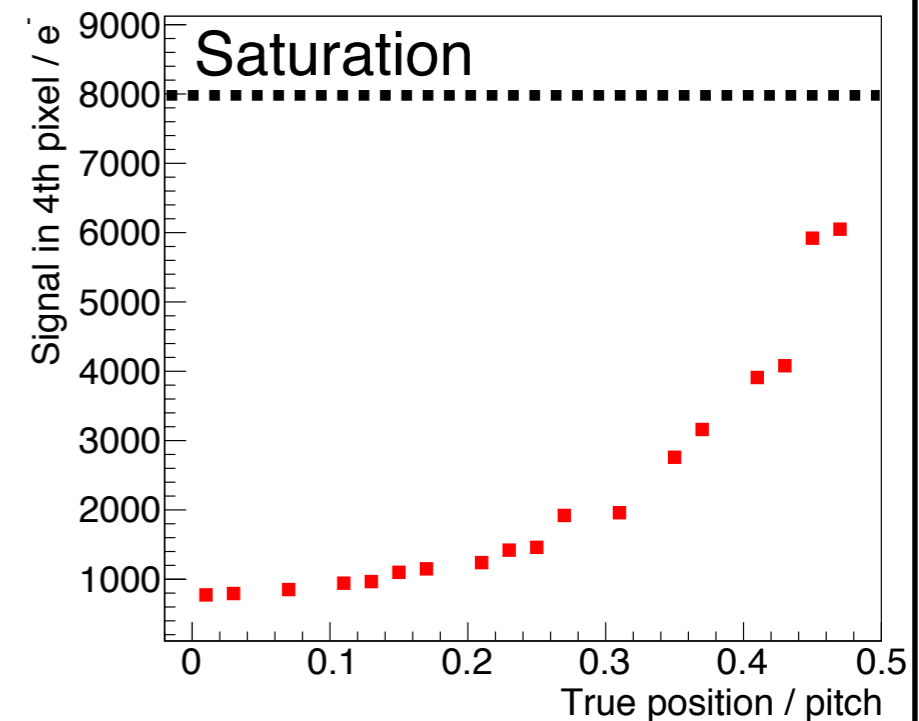
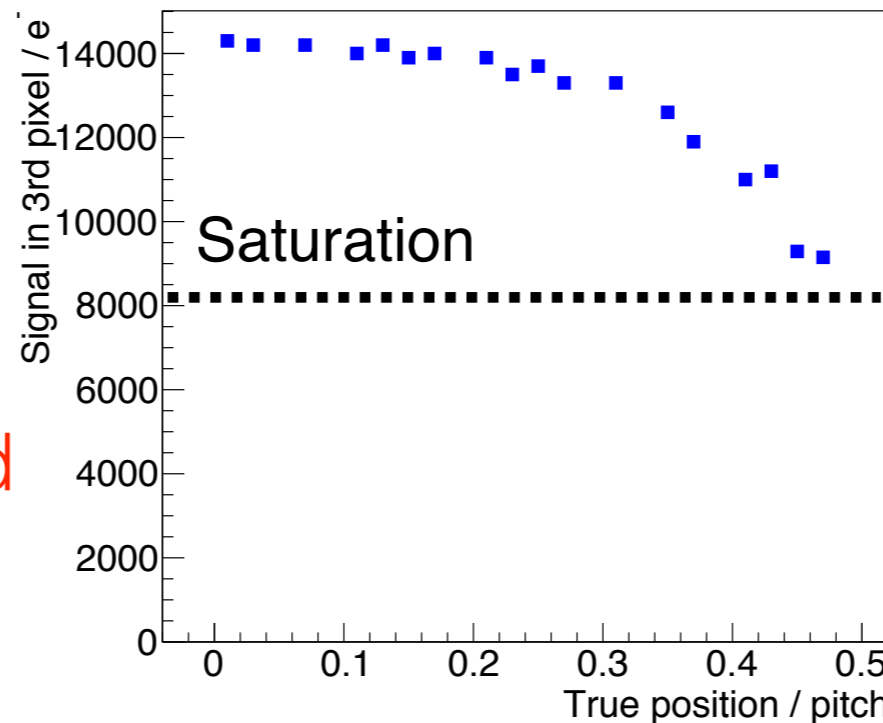


1-pixel cluster
saturation

2-pixel cluster
saturation

Check in simulation:

- One strip/pixel always saturated
- One strip/pixel mostly non-saturated



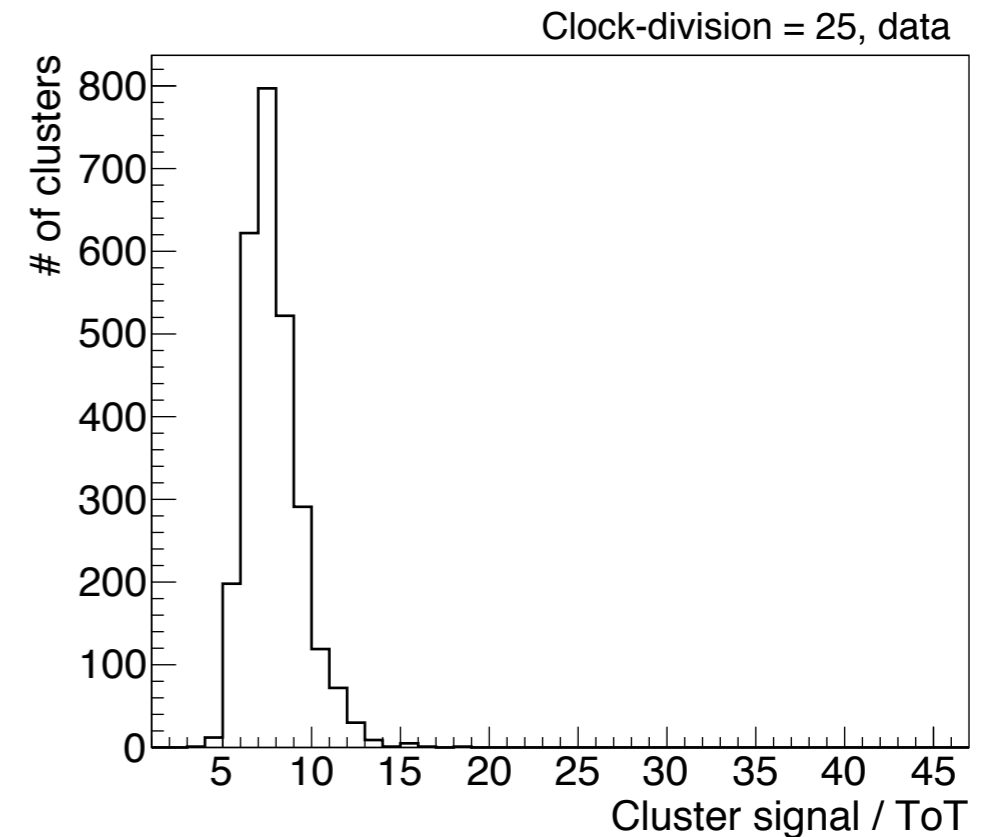
Distortion of CoG

But eta-correction corrects for non all linearities

Resolution versus clock division / even

Why does the resolution not gets worse for large clock-divisions?:

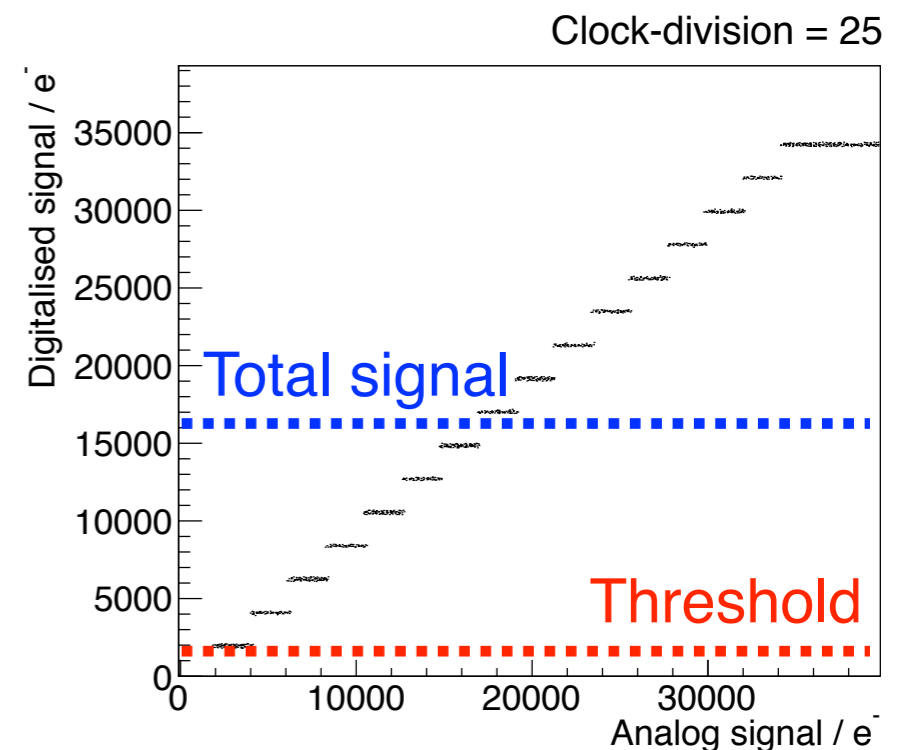
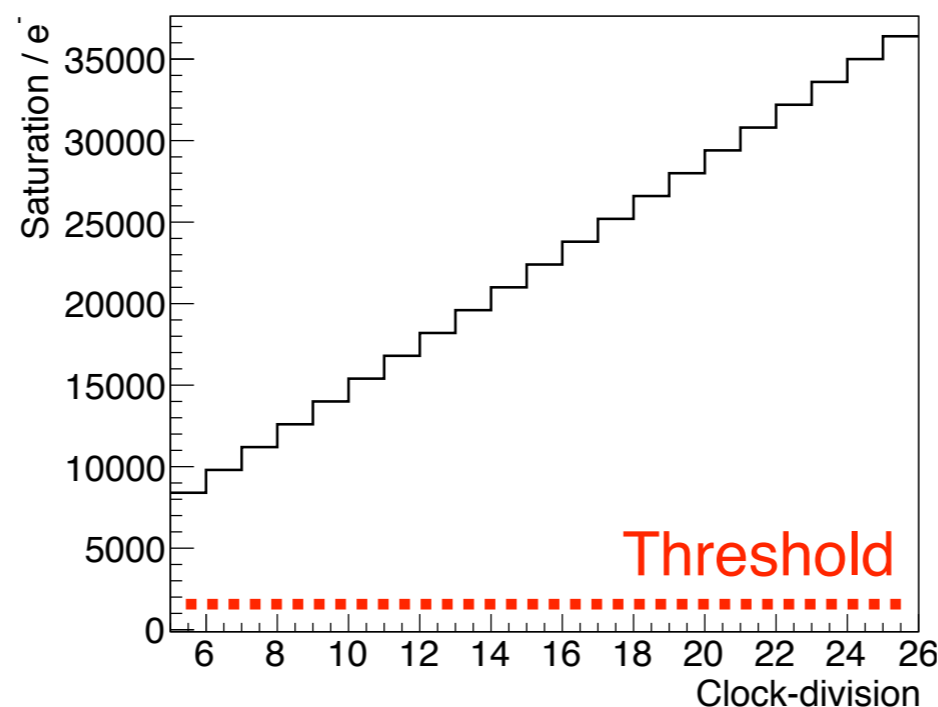
- For a clock division of 25 one still gets precise enough Landau distribution



Check in simulation:

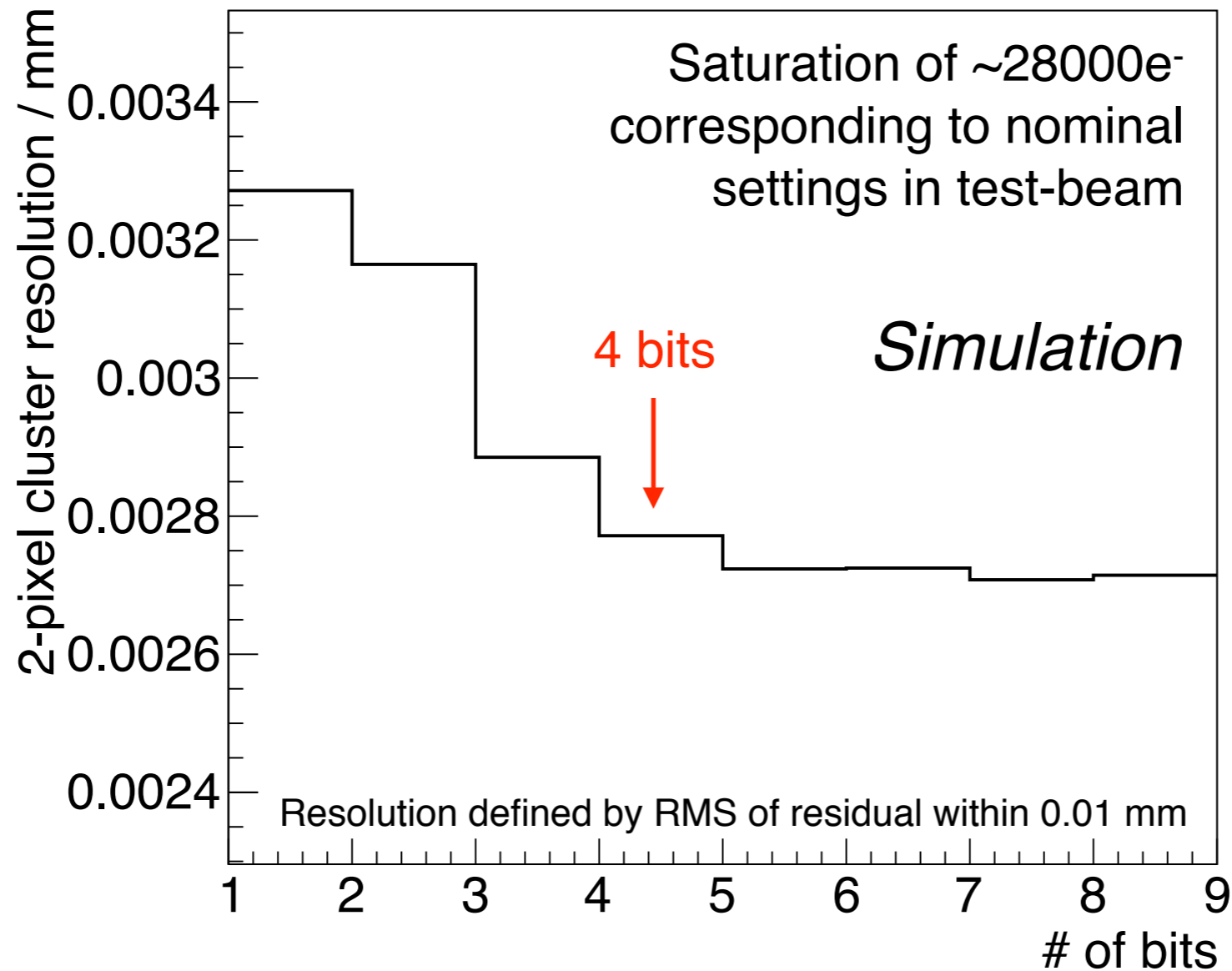


Do we need 4-bits
or are less bits
sufficient?



Resolution versus number of bits / simulation

First look to answer the questions how many bits are optimal:



↳ For the clock-division and the sensor used in the test-beam
4 bits seem to be kind of optimal

Summary & outlook

Simulation of digitalisation implemented and validated:

- ↳ Good agreement with test-beam data from CLICpix planar-sensor clock-scan for:
 - Landau distributions
 - Resolution
- ↳ Simulation helps to understand results

Simulation framework validated for:

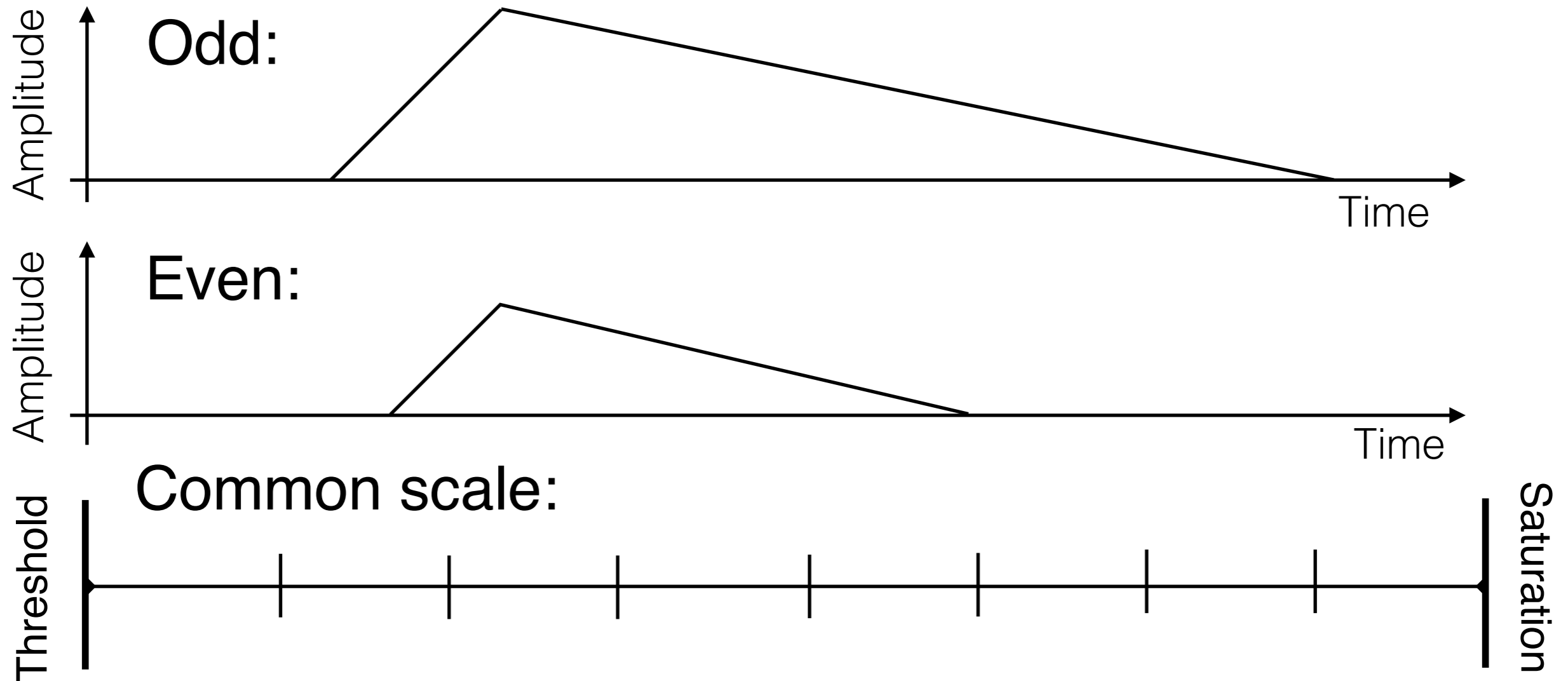
- Different chips (Timepix1 & CLICpix)
- Different sensor thicknesses
- Different incident angle
- Magnetic field
- Different thresholds
- Digitalisation

Framework finally fully validated

Can use the framework now to study performance of different designs

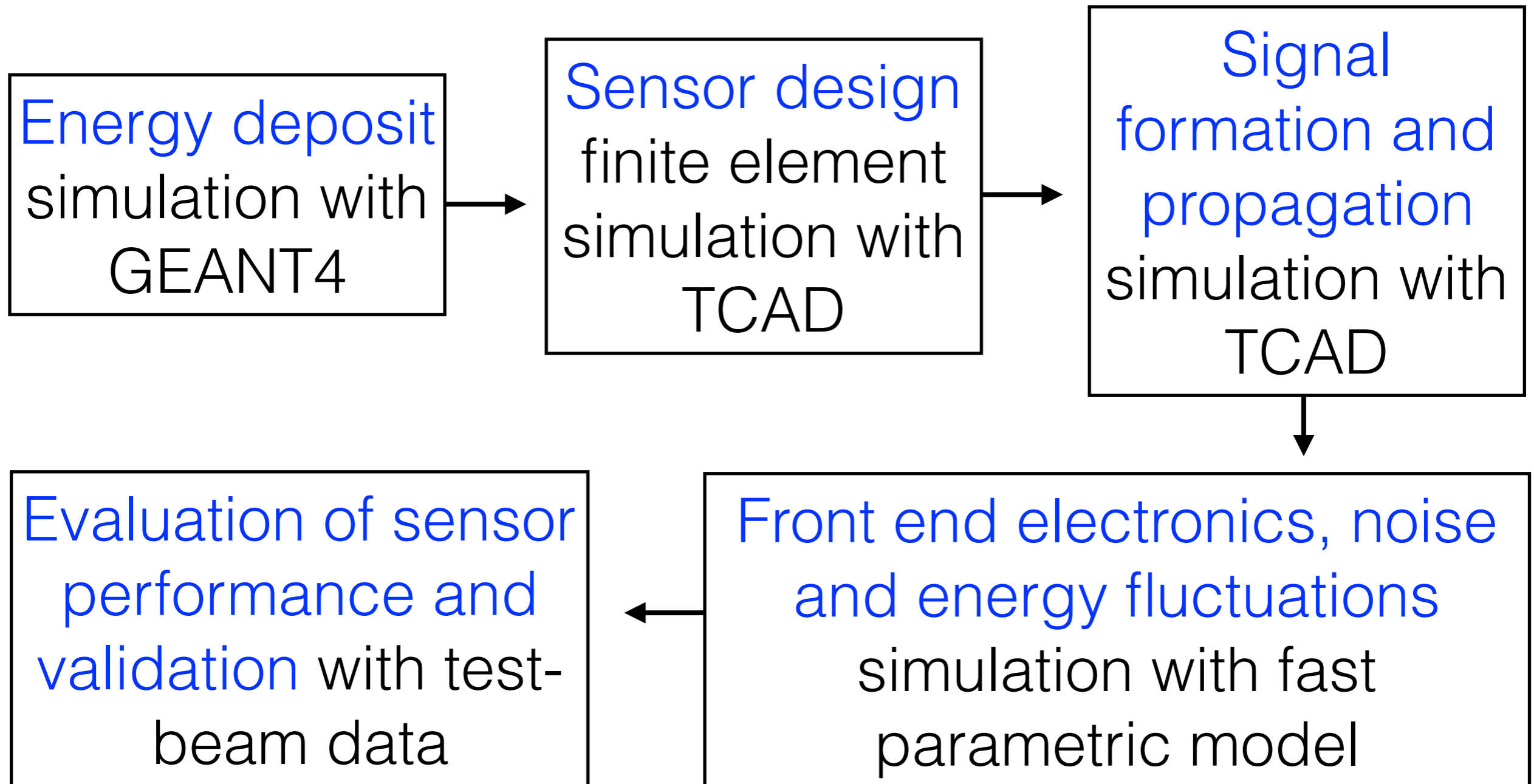
BACKUP

Effect of difference in even & odd columns



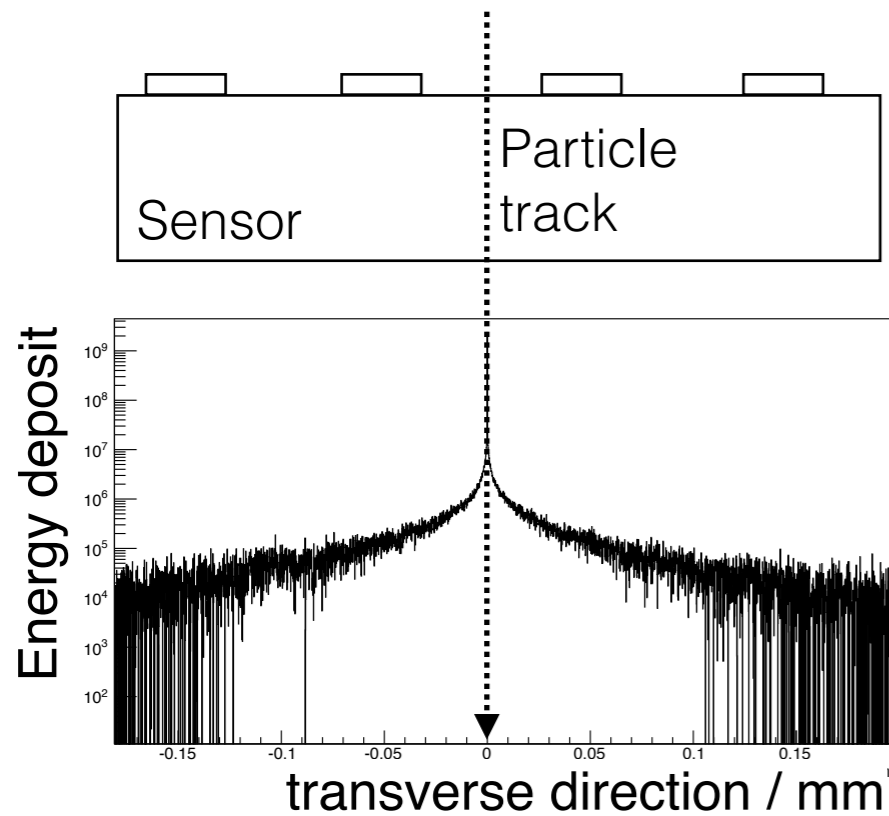
- Even (low charge) refers to nominal condition (without additional charge injected)
- Odd refers to additional injected charge
- This is just a change of the pulse form and leaves the parameter of Threshold & Saturation unchanged
- Calibrate digitalisation scale to even columns and inject charge before threshold application in simulation to compare to odd columns

My workflow for the simulation of tracking sensors

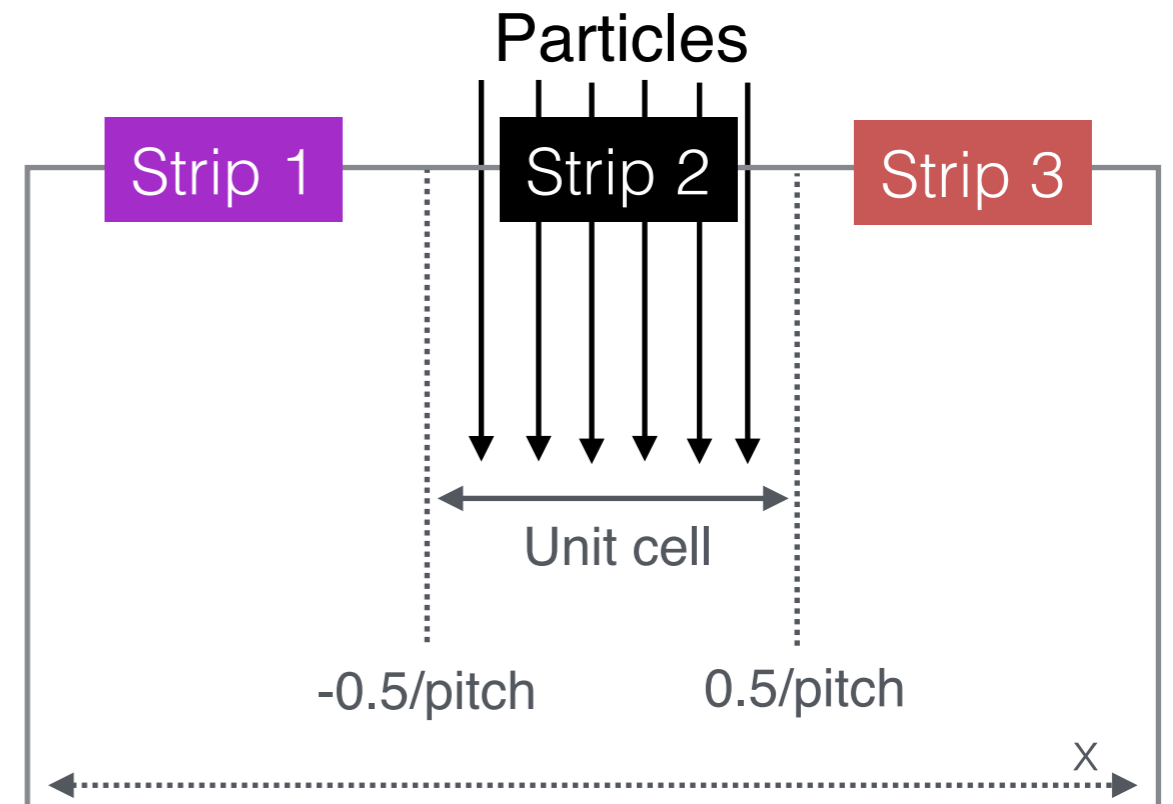


Simulation of particle signal in sensor

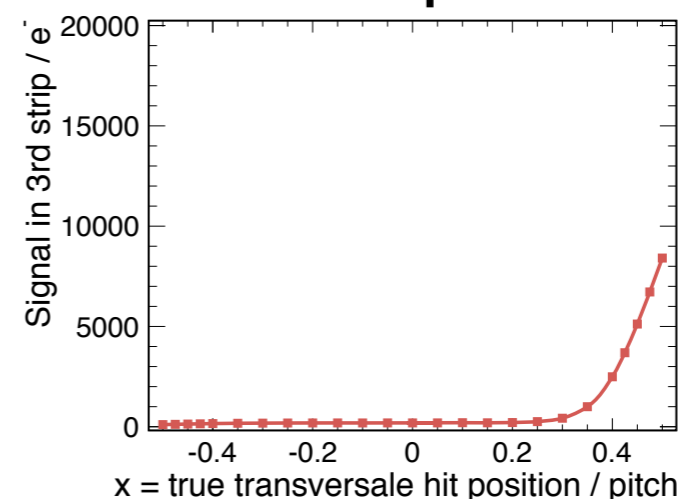
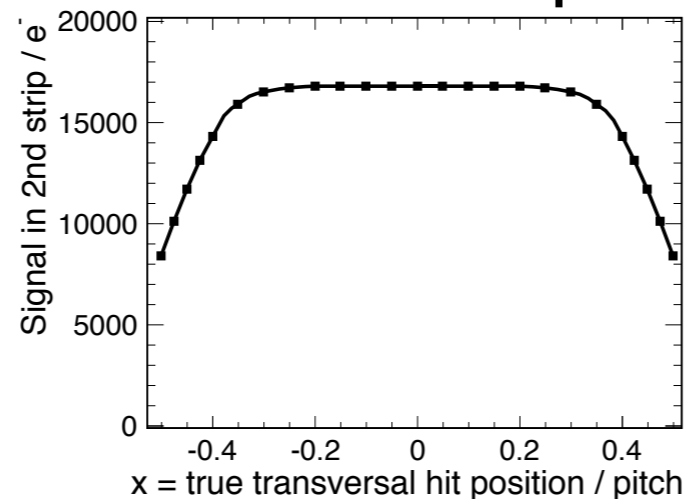
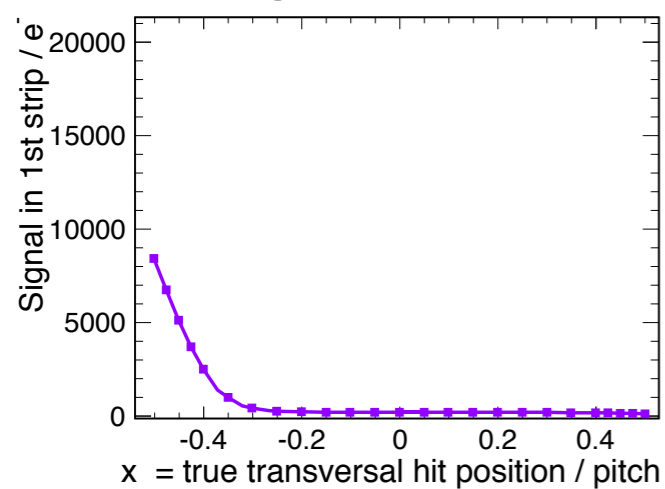
GEANT4 simulation of energy deposit in silicon sensor:



Finite element simulation of sensor with T-CAD:

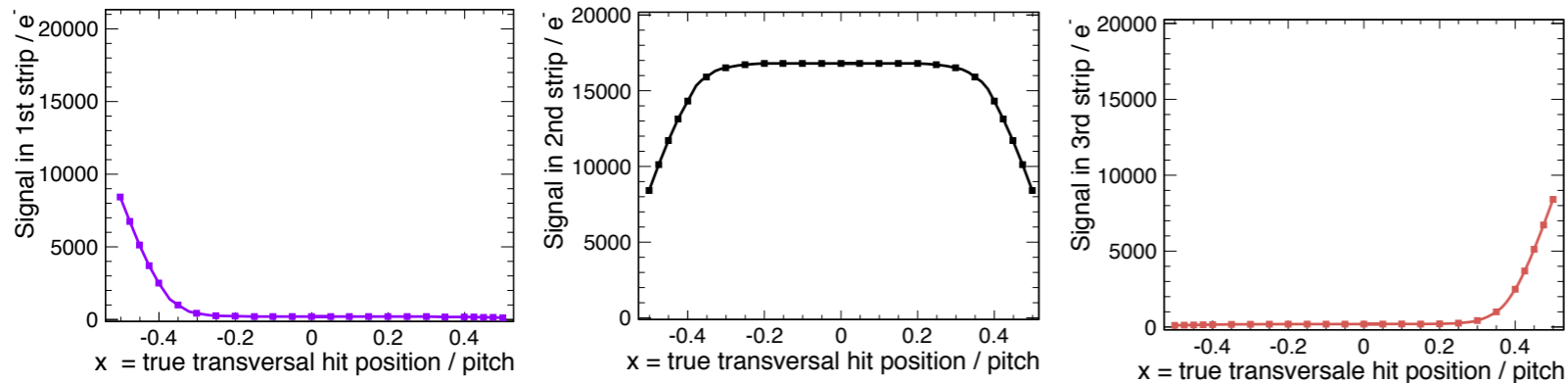


Fit to signal on different readout strips vs. transversal position x:



Fast parametric model of front end electronics, energy fluctuations and noise

- Start with fit to signal on readout strips



- Scan x with small step size, perform for each position:

1.) Landau smearing of sum of signal (energy fluctuations)

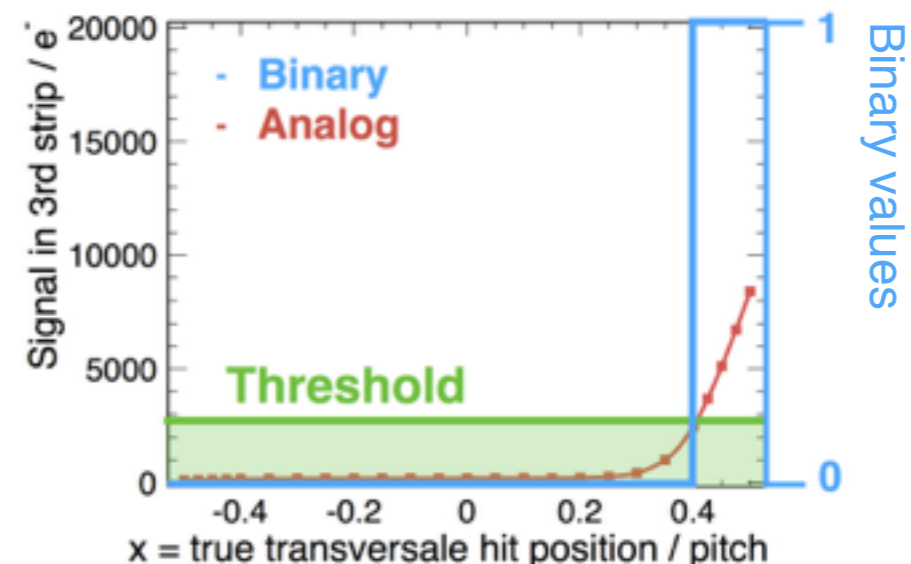
(Use Landau distribution from GEANT4 simulation)

2.) Gauss smearing of single strip signal (electronic noise)

3.) Threshold application

4.) Digitalisation

- Analog
- Digital, adjust # of bits & saturation
- Binary, just two bit-states (1 bit)



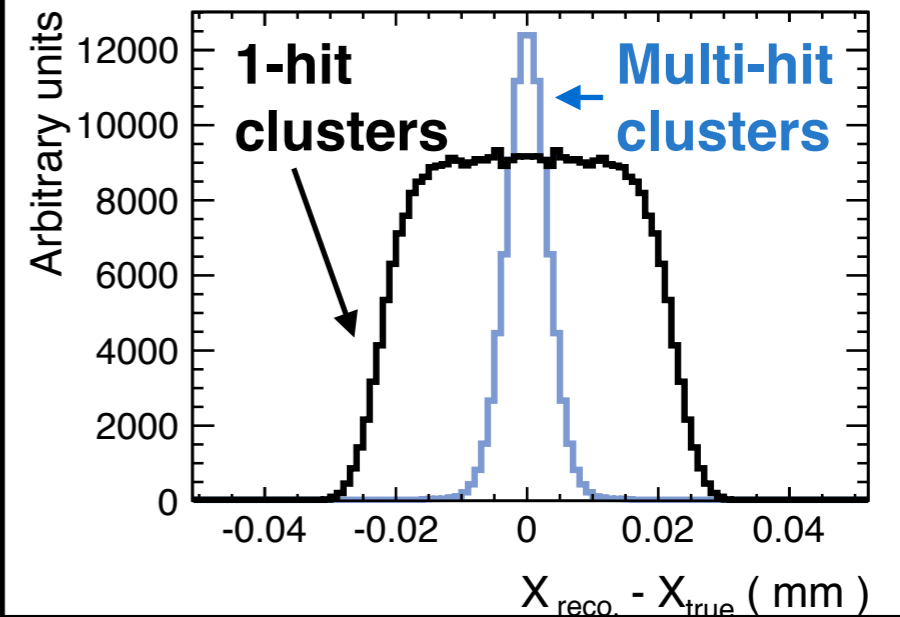
Position reconstruction

Start with **C**enter **o**f **G**ravity (CoG):

$$\text{CoG} = \frac{\sum_{i \in \{\text{strips}\}} \text{position}_i \cdot \text{signal}_i}{\sum_{i \in \{\text{strips}\}} \text{signal}_i}$$

Binary:
- Nothing more -

CoG-corrected residual:



Analog or digital:

- **CoG-correction:**

